

Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/047,177	LAI, YHEAN-SEN
	Examiner	Art Unit
	Erin M. File	2634

ISSUE CLASSIFICATION				
ORIGINAL		CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	
375	348	375	285	316
INTERNATIONAL CLASSIFICATION		327	310	384
H 0 3 D	1/06	348	607	551
H 0 3 D	11/04	455	296	
H 0 3 K	5/01			
H 0 3 K	6/04			
H 0 4 L	25/08			
Erin M. File 11/18/2005 (Assistant Examiner) (Date)		STEPHEN CHIN 11/24/05 SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)		Total Claims Allowed: 21
J. Mark 12/1/05 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s) 2	O.G. Print Fig. 1	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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